

August 29, 2016

Subject: PCN#12A-16 Notification of Intent to Utilize an Alternate Qualified Test Site for the iCE40 Ultra, iCE40 UltraLite, and LIF-UC120 WLCSP Package Devices

Dear Lattice Customer,

Lattice is providing this 90-day Notification of our intent to utilize an alternate qualified test site for the iCE40 Ultra[™], iCE40 UltraLite[™], and LIF-UC[™]120 devices in Wafer Level Chip Scale Package (WLCSP) devices.

In an effort to expand our test capacity for high-running devices, Lattice will now use King Yuan Electronics Co. Ltd. (KYEC), Chu-Nan, Taiwan for select devices. KYEC will use the same Automated Test Equipment (ATE), test hardware and test program software as is currently used at other Lattice test sites. Devices tested at KYEC will meet all existing specifications.

Affected Products

The Ordering Part Numbers (OPNs) affected by this PCN are listed below. This PCN also affects any custom devices (i.e. factory programmed, special test, tape and reel, non-standard speed grade and package, etc.), which are derived from any of the devices listed in the table.

Product Line	Ordering Part Number (OPNs)	Package Type
ICE40UL640	ICE40UL640-SWG16ITR	16-Ball WLCSP
	ICE40UL640-SWG16ITR1K	
	ICE40UL640-SWG16ITR50	
ICE40UL1K	ICE40UL1K-SWG16ITR	16-Ball WLCSP
	ICE40UL1K-SWG16ITR1K	
	ICE40UL1K-SWG16ITR50	
ICE5LP1K	ICE5LP1K-SWG36ITR	36-Ball WLCSP
	ICE5LP1K-SWG36ITR50	
	ICE5LP1K-SWG36ITR1K	
ICE5LP2K	ICE5LP2K-SWG36ITR	36-Ball WLCSP
	ICE5LP2K-SWG36ITR50	
	ICE5LP2K-SWG36ITR1K	
ICE5LP4K	ICE5LP4K-SWG36ITR	36-Ball WLCSP
	ICE5LP4K-SWG36ITR50	
	ICE5LP4K-SWG36ITR1K	
LIF-UC120	LIF-UC120-SWG36ITR	36-Ball WLCSP
	LIF-UC120-SWG36ITR50	
	LIF-UC120-SWG36ITR1K	

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Device Identification

Devices tested at KYEC, Taiwan can be identified by the 6th character ("**E**") of the datecode marked on the topside of the devices. This datecode is also marked on the label on the outside of the inventory box as well as on the anti-static, moisture barrier bag within. See device topside marking examples below:



Datasheet Specifications

This PCN has no impact on any datasheet specifications.

Sample Requests

This PCN only pertains the additional qualified test site for Lattice products and there are no changes to the device material set, fit, form and function of the product; therefore, samples will not be available.

Response

No customer response is required. If customers have questions about the datasheet changes described above, they should contact their local field support for further assistance.

KYEC tested devices will start shipping 90 days from this notice date, that is by November 29, 2016.

Lattice PCNs are available on the <u>Lattice PCN web page</u>. Please sign up to receive e-mail PCN alerts by registering <u>here</u>. If you already have a Lattice web account and wish to receive PCN alerts, you can do so by logging into <u>your account</u> and making edits to your subscription options.

Contact

If you have any questions or require additional information, please contact pcn@latticesemi.com.

Sincerely,

Lattice Semiconductor PCN Administration

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